CD74FCT245T, CD74FCT640T, CD74FCT2245T

December 1996

Fast CMOS Octal Bidirectional Transceivers

Features

- Advanced 0.8 micron CMOS Technology
- These Devices are Pin Compatible With Bipolar FAST™ Series at a Higher Speed and Lower Power Consumption
- 25Ω Series Resistor on All Outputs (CD74FCT2245T)
- TTL input and output levels
- Low ground bounce outputs
- Extremely low static power
- Hysteresis on all inputs

Description

These devices are 8-bit wide octal buffer bidirectional transceivers designed for asynchronous two-way communication between data buses. The transmit/receive (T/$\overline{R}$) input determines the direction of data flow through the bidirectional transceiver. Transmit (active HIGH) enables data from A ports to B ports, and receive (active LOW) from B ports to A ports. The output enable ($\overline{OE}$) input, when HIGH, disables both A and B ports by placing them in HIGH Z condition

All CD74FCT2245T devices have a built-in 25Ω series resistor on all outputs to reduce noise due to reflections, thus eliminating the need for an external terminating resistor.

Ordering Information

PART NUMBER	TEMP. RANGE (^{o}C)	PACKAGE	PKG. NO.
CD74FCT245ATM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT245ATQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT245CTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT245CTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT245DTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT245DTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT245TM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT245TQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT640ATM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT640ATQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT640CTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT640CTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT640DTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT640DTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT640TM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT640TQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT2245ATM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT2245ATQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT2245CTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT2245CTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT2245TM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT2245TQM	-40 to 85	20 Ld QSOP	M20.15-P

NOTE: When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

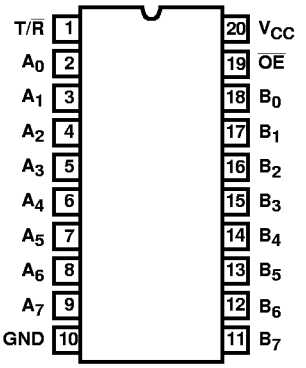
CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

FAST™ is a trademark of Fairchild Semiconductor.

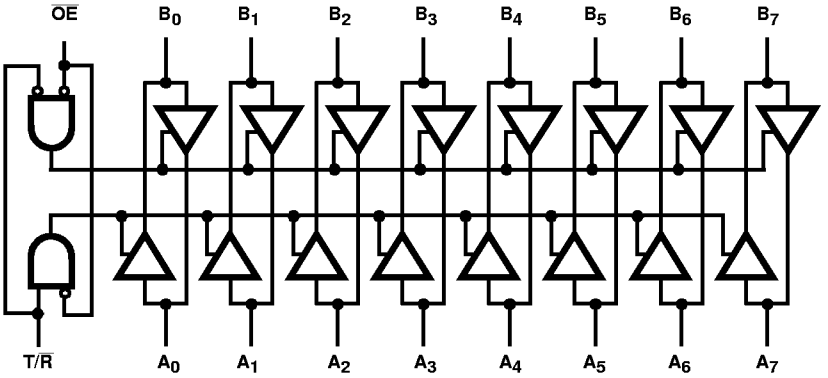
File Number **4168.2**

Pinout

CD74FCT245T, CD74FCT640T, CD74FCT2245
(QSOP, SOIC)
TOP VIEW



Functional Block Diagram



NOTE: CD74FCT245T, CD74FCT2245T are non-inverting options. CD74FCT640T is the inverting option.

TRUTH TABLE (NOTE 1)

INPUTS		OUTPUTS
$\overline{OE}$	T/$\overline{R}$	
L	L	Bus B Data to Bus A (NOTE 2)
L	H	Bus A Data to Bus B (NOTE 2)
H	X	High Z State

NOTES:

1. H = HIGH Voltage Level
   L = LOW Voltage Level
   X = Don't Care
   Z = High Impedance
2. CD74FCT640T is inverting from input to output.

Pin Descriptions

PIN NAME	DESCRIPTION
$\overline{OE}$	Three-State Output Enable Inputs (Active LOW)
T/$\overline{R}$	Transmit/Receive Input
A_0-A_7	Side A Inputs or three-State Outputs
B_0-B_7	Side B Inputs or three-State Outputs
GND	Ground
V_{CC}	Power

Absolute Maximum Ratings

DC Input Voltage . . . . . -0.5V to 7.0V
DC Output Current 120mA

Operating Conditions

Operating Temperature Range . . . . . -40^oC to 85^oC
Supply Voltage to Ground Potential
Inputs and V_{CC} Only . . . . . -0.5V to 7.0V
Supply Voltage to Ground Potential
Outputs and D/O Only. . . . . -0.5V to 7.0V

Thermal Information

Thermal Resistance (Typical, Note 3)	θ_{JA} ($^oC/W$)
SOIC Package	87
QSOP Package	110

Maximum Junction Temperature . . . . . 150^oC
Maximum Storage Temperature Range . . . . . -65^oC to 150^oC
Maximum Lead Temperature (Soldering 10s) . . . . . 300^oC
(Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

PARAMETERS	SYMBOL	(NOTE 4) TEST CONDITIONS		MIN	(NOTE 5) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, $T_A = -40^oC$ to 85^oC, $V_{CC} = 5.0V \pm 5\%$							
Output HIGH Voltage	V_{OH}	V_{CC} = Min, $V_{IN} = V_{IH}$ or V_{IL}	I_{OH} = -15.0mA	2.4	3.0	-	V
Output LOW Voltage	V_{OL}	V_{CC} = Min, $V_{IN} = V_{IH}$ or V_{IL}	I_{OL} = 64mA	-	0.3	0.50	V
Output LOW Voltage	V_{OL}	V_{CC} = Min, $V_{IN} = V_{IH}$ or V_{IL}	I_{OL} = 12mA (25Ω Series)	-	0.3	0.50	V
Input HIGH Voltage	V_{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage	V_{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Input HIGH Current	I_{IH}	(Except I/O pins) V_{CC} = Max	$V_{IN} = V_{CC}$	-	-	1	µA
Input LOW Current	I_{IL}	(Except I/O pins) V_{CC} = Max	V_{IN} = GND	-	-	-1	µA
Input HIGH Current	I_{IH}	(I/O pins only) V_{CC} = Max	$V_{IN} = V_{CC}$	-	-	1	µA
Input LOW Current	I_{IL}	(I/O pins only) V_{CC} = Max	V_{IN} = GND	-	-	-1	µA
HIGH Impedance Output Current	I_{OZH}	V_{CC} = Max	V_{OUT} = 2.7V	-	-	1	µA
	I_{OZL}		V_{OUT} = 0.5V	-	-	-1	µA
Clamp Diode Voltage	V_{IK}	V_{CC} = Min, I_{IN} = -18mA		-	-0.7	-1.2	V
Short Circuit Current	I_{OS}	V_{CC} = Max (Note 6), V_{OUT} = GND		-60	-120	-	mA
Power Down Disable	I_{OFF}	V_{CC} = GND, V_{OUT} = 4.5V		-	-	100	µA
Input Hysteresis	V_H			-	200	-	mV
CAPACITANCE $T_A = 25^oC$, f = 1MHz							
Input Capacitance (Note 7)	C_{IN}	V_{IN} = 0V		-	6	10	pF
Output Capacitance (Note 7)	C_{OUT}	V_{OUT} = 0V		-	8	12	pF

Electrical Specifications (Continued)

PARAMETERS	SYMBOL	(NOTE 4) TEST CONDITIONS		MIN	(NOTE 5) TYP	MAX	UNITS
POWER SUPPLY SPECIFICATIONS							
Quiescent Power Supply Current	I_{CC}	V_{CC} = Max	V_{IN} = GND or V_{CC}	-	0.1	500	µA
Supply Current per Input at TTL HIGH	ΔI_{CC}	V_{CC} = Max	V_{IN} = 3.4V (Note 8)	-	0.5	2.0	mA
Supply Current per Input per MHz (Note 9)	I_{CCD}	V_{CC} = Max, Outputs Open $\overline{OE}$=GND T/$\overline{R}$=GND or V_{CC} One Input Toggling 50% Duty Cycle	V_{IN} = V_{CC} V_{IN} = GND	-	0.15	0.25	mA/ MHz
Total Power Supply Current (Note 11)	I_C	V_{CC} = Max, Outputs Open f_T = 10MHz, 50% Duty Cycle T/$\overline{R}$=$\overline{OE}$=GND One Bit toggling	V_{IN} = V_{CC} V_{IN} = GND	-	1.5	3.5 (Note 10)	mA
			V_{IN} = 3.4V V_{IN} = GND	-	1.8	4.5 (Note 10)	mA
		V_{CC} = Max, Outputs Open f_T = 2.5MHz, 50% Duty Cycle T/$\overline{R}$=$\overline{OE}$=GND Eight Bits toggling	V_{IN} = V_{CC} V_{IN} = GND	-	3.0	6.0 (Note 10)	mA
			V_{IN} = 3.4V V_{IN} = GND	-	5.0	14.0 (Note 10)	mA

Switching Specifications Over Operating Range

PARAMETER	SYMBOL	(NOTE 12) TEST CONDITIONS	T		AT		CT		DT		UNITS
			(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	
CD74FCT245T, CD74FCT2245T											
Propagation Delay A to B, B to A	t_{PLH}, t_{PHL}	C_L = 50pF R_L = 500Ω	1.5	7.0	1.5	4.6	1.5	4.1	1.5	3.8	ns
Output Enable Time $\overline{OE}$ to A or B	t_{PZH}, t_{PZL}	C_L = 50pF R_L = 500Ω	1.5	9.0	1.5	6.2	1.5	5.8	1.5	5.0	ns
Output Disable Time $\overline{OE}$ to A or B (Note 14)	t_{PHZ}, t_{PLZ}	C_L = 50pF R_L = 500Ω	1.5	7.5	1.5	5.0	1.5	4.8	1.5	4.3	ns
Output Enable Time T/$\overline{R}$ to A or B	t_{PZH}, t_{PZL}	C_L = 50pF R_L = 500Ω	1.5	9.0	1.5	6.2	1.5	5.8	1.5	5.0	ns
Output Disable Time T/$\overline{R}$ to A or B (Note 14)	t_{PHZ}, t_{PLZ}	C_L = 50pF R_L = 500Ω	1.5	7.5	1.5	5.0	1.5	4.8	1.5	4.3	ns
CD74FCT640T											
Propagation Delay A to B, B to A	t_{PLH}, t_{PHL}	C_L = 50pF R_L = 500Ω	2	7.0	1.5	5.0	1.5	4.4	1.5	3.7	ns
Output Enable Time $\overline{OE}$ to A or B	t_{PZH}, t_{PZL}	C_L = 50pF R_L = 500Ω	2	13.0	1.5	6.2	1.5	5.8	1.5	5.0	ns
Output Disable Time $\overline{OE}$ to A or B (Note 14)	t_{PHZ}, t_{PLZ}	C_L = 50pF R_L = 500Ω	2	10.0	1.5	5.0	1.5	4.8	1.5	4.3	ns

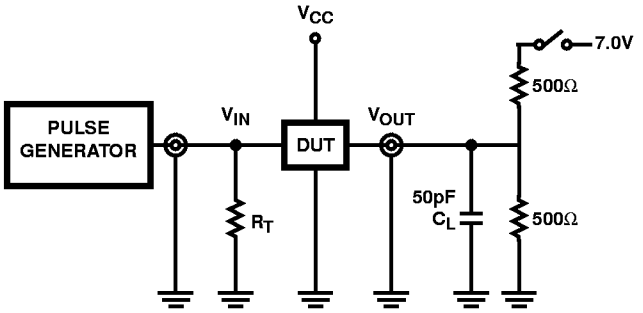
Switching Specifications Over Operating Range (Continued)

PARAMETER	SYMBOL	(NOTE 12) TEST CONDITIONS	T		AT		CT		DT		UNITS
			(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	(NOTE 13) MIN	MAX	
Output Enable Time $T/\overline{R}$ to A or B	t_{PZH}, t_{PZL}	C_L = 50pF R_L = 500Ω	2	13.0	1.5	6.2	1.5	5.8	1.5	5.0	ns
Output Disable Time $T/\overline{R}$ to A or B (Note 14)	t_{PHZ}, t_{PLZ}	C_L = 50pF R_L = 500Ω	2	10.0	1.5	5.0	1.5	4.8	1.5	4.3	ns

NOTES:

4. For conditions shown as Max or Min, use appropriate value specified under Electrical Characteristics for the applicable device type.
5. Typical values are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
6. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
7. This parameter is determined by device characterization but is not production tested.
8. Per TTL driven input (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.
9. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
10. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
11. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
    $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_I N_I)$
    I_{CC} = Quiescent Current
    ΔI_{CC} = Power Supply Current for a TTL High Input (V_{IN} = 3.4V)
    D_H = Duty Cycle for TTL Inputs High
    N_T = Number of TTL Inputs at D_H
    I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
    f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)
    f_I = Input Frequency
    N_I = Number of Inputs at f_I
    All currents are in milliamps and all frequencies are in megahertz.
12. See test circuit and wave forms.
13. Minimum limits are guaranteed but not tested on Propagation Delays.
14. This parameter is guaranteed but not production tested.

Test Circuits and Waveforms



SWITCH POSITION

TEST	SWITCH
t_{PLZ}, t_{PZL}	Closed
t_{PHZ}, t_{PZH}, t_{PLH}, t_{PHL}	Open

DEFINITIONS:

C_L = Load capacitance, includes jig and probe capacitance.

R_T = Termination resistance, should be equal to Z_{OUT} of the Pulse Generator.

NOTE:

15. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z_{OUT} ≤ 50Ω; t_f, t_r ≤ 2.5ns.

FIGURE 1. TEST CIRCUIT

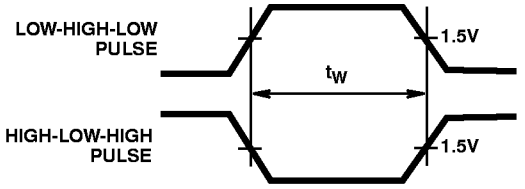


FIGURE 2. PULSE WIDTH

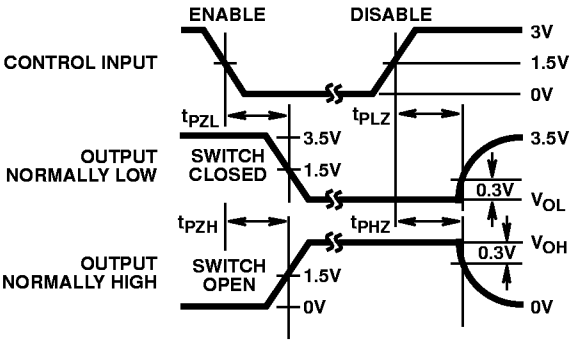


FIGURE 3. ENABLE AND DISABLE TIMING

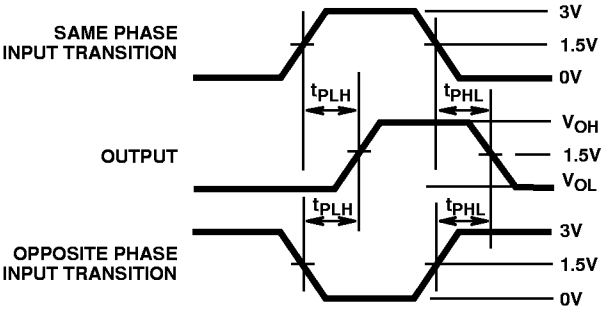


FIGURE 4. PROPAGATION DELAY